

Description

The AP50P03D uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.

General Features

 $V_{DS} = -30V I_{D} = -50A$

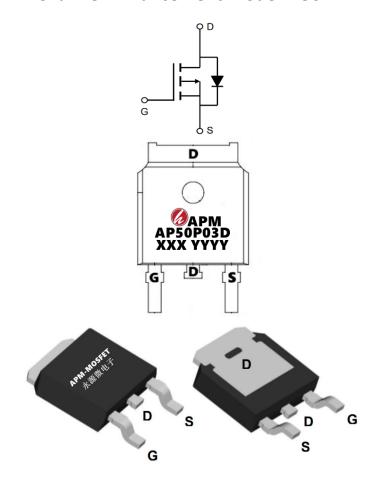
 $R_{DS(ON)}$ <16m Ω @ V_{GS} =-10V (Type: 10.5m Ω)

Application

Lithium battery protection

Wireless impact

Mobile phone fast charging



Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
AP50P03D	TO-252-3L	AP50P03D XXX YYYY	5000

Absolute Maximum Ratings (TC=25℃unless otherwise noted)

Symbol	Parameter	Rating	Units	
VDS	Drain-Source Voltage	-30	V	
VGS	Gate-Source Voltage	±20	V	
I D@T _A =25℃	Continuous Drain Current, V _{GS} @ -10V ¹	-50	Α	
I _D @T _A =70°C	Continuous Drain Current, V _{GS} @ -10V ¹	-23	А	
IDM	Pulsed Drain Current ²	-120	Α	
EAS	Single Pulse Avalanche Energy ³	68	mJ	
IAS	Avalanche Current	-29.4	Α	
P _D @T _A =25°C	Total Power Dissipation⁴	310	W	
TSTG	Storage Temperature Range	-55 to 150	$^{\circ}\mathbb{C}$	
TJ	Operating Junction Temperature Range	-55 to 150	$^{\circ}\mathbb{C}$	
R₀JA	Thermal Resistance Junction-Ambient ¹	62.5	°C/W	
R₀JC	Thermal Resistance Junction-Case ¹	24	°C/W	





Electrical Characteristics (T_J=25°C, unless otherwise noted)

Symbol	Parameter	Test Condition	Min.	Тур.	Max.	Units	
V(BR)DSS	Drain-Source Breakdown Voltage	V _{GS} =0V, I _D = -250μA	-30	-32.5	-	V	
IDSS	Zero Gate Voltage Drain Current	V _{DS} = -30V, V _{GS} =0V,	-	-	-1	μΑ	
IGSS	Gate to Body Leakage Current	V _{DS} =0V, V _{GS} = ±20V	-	-	±100	nA	
VGS(th)	Gate Threshold Voltage	V _{DS} =V _{GS} , I _D = -250μA	-1.2	-1.5	-2.5	V	
DDC()	Static Drain-Source on-Resistance	V _{GS} = -10V, I _D = -10A	-	10.5	16	0	
RDS(on)	note3	V _{GS} = -4.5V, I _D = -5A	-	16	20	mΩ	
Rg	Gate Resistance	V _{DS} =0V , V _{GS} =0V , f=1MHz	4.9	7.0	9.1	Ω	
Ciss	Input Capacitance	V = 24V V =40V	-	2130	-	pF	
Coss	Output Capacitance	V_{DS} = -24V, V_{GS} =10V, f=1.0MHz	-	280	-	pF	
Crss	Reverse Transfer Capacitance		-	252	-	рF	
Qg	Total Gate Charge)/ O4)/ L 4A	-	22	-	nC	
Q _{gs}	Gate-Source Charge	V _{DS} = -24V, I _D = -1A, V _{GS} = -10V	-	4	-	nC	
Q _{gd}	Gate-Drain("Miller") Charge		-	5.8	-	nC	
td(on)	Turn-on Delay Time		-	9	-	ns	
t _r	Turn-on Rise Time	V _{DD} = -24V, I _D = -1A,	-	13	-	ns	
td(off)	Turn-off Delay Time	V_{GS} = -10V, R_{GEN} =7.0 Ω	-	48	-	ns	
t _f	Turn-off Fall Time		-	20	-	ns	
IS	Maximum Continuous Drain to Source Diode Forward Current			-	-29.5	Α	
ISM	Maximum Pulsed Drain to Source Diode Forward Current		-	-	-44	Α	
VSD	Drain to Source Diode Forward Voltage V _{GS} =0V, I _S = -1A		-	-0.74	-1.2	V	

Note:

- 1. The data tested by surface mounted on a 1 inch 2 FR-4 board with 2OZ copper.
- $2\sqrt{100}$ The data tested by pulsed , pulse width .The EAS data shows Max. rating .
- 3、The power dissipation is limited by 175 $^{\circ}\mathrm{C}$ junction temperature
- 4 EAS condition: $T_J=25$ °C, $V_{DD}=-24V$, $V_G=-10V$, $R_G=7\Omega$, L=0.1mH, $I_{AS}=-29.5$ A
- 5. The data is theoretically the same as ID and IDM, in real applications, should be limited by total power dissipation.



Typical Characteristics

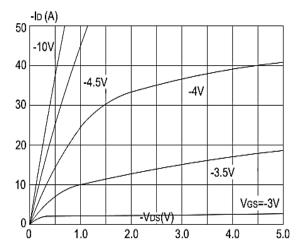


Figure1: Output Characteristics Figure

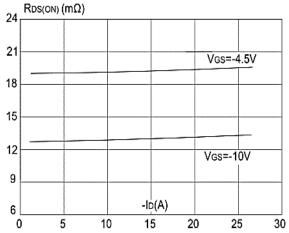


Figure 3:On-resistance vs. Drain Current

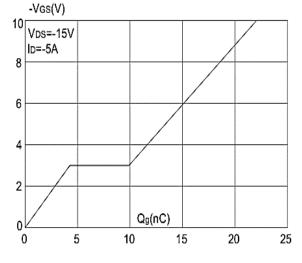


Figure 5: Gate Charge Characteristics

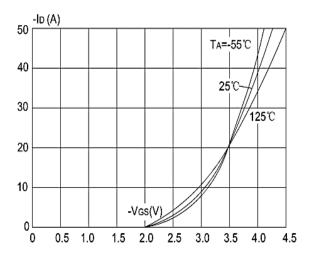


Figure2: Typical Transfer Characteristics

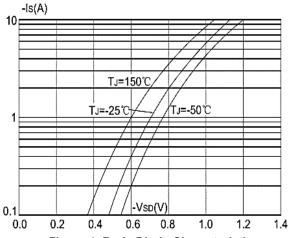


Figure 4: Body Diode Characteristics

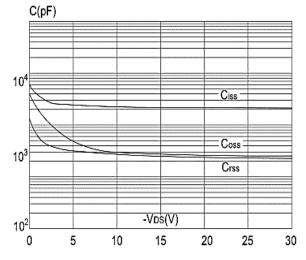


Figure 6: Capacitance Characteristics





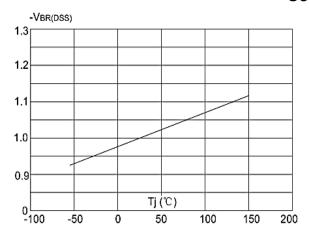


Figure 7: Normalized Breakdown Voltage vs. Junction Temperature

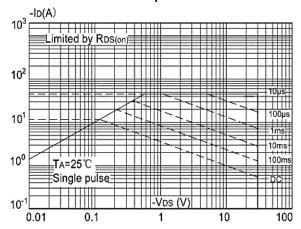


Figure 9: Maximum Safe Operating Area

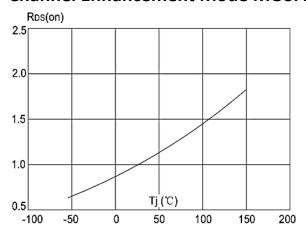


Figure 8: Normalized on Resistance vs. Junction Temperature

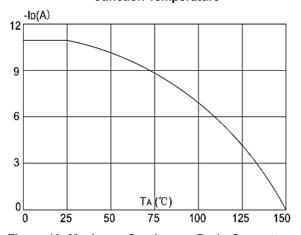


Figure 10: Maximum Continuous Drain Current vs. Ambient Temperature

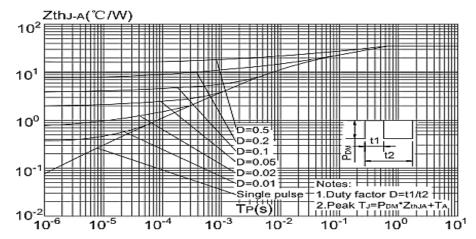
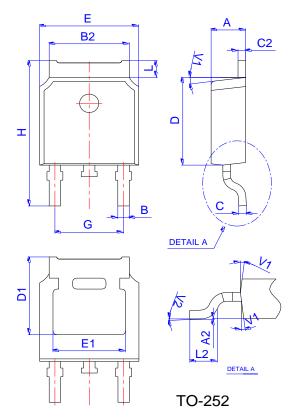


Figure.11: Maximum Effective Transient Thermal Impedance, Junction-to-Ambient

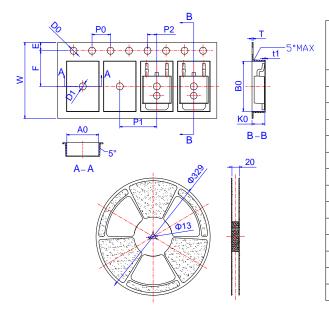


Package Mechanical Data:TO-252-3L



	Dimensions					
Ref.	Millimeters		Inches			
	Min.	Тур.	Max.	Min.	Тур.	Max.
Α	2.10		2.50	0.083		0.098
A2	0		0.10	0		0.004
В	0.66		0.86	0.026		0.034
B2	5.18		5.48	0.202		0.216
С	0.40		0.60	0.016		0.024
C2	0.44		0.58	0.017		0.023
D	5.90		6.30	0.232		0.248
D1	5.30REF			0.209REF		
E	6.40		6.80	0.252		0.268
E1	4.63			0.182		
G	4.47		4.67	0.176		0.184
Н	9.50		10.70	0.374		0.421
L	1.09		1.21	0.043		0.048
L2	1.35		1.65	0.053		0.065
V1		7°			7°	
V2	0°		6°	0°		6°

Reel Spectification-TO-252



	Dimensions					
Ref.		Millimeters		Inches		
	Min.	Тур.	Max.	Min.	Тур.	Max.
W	15.90	16.00	16.10	0.626	0.630	0.634
Е	1.65	1.75	1.85	0.065	0.069	0.073
F	7.40	7.50	7.60	0.291	0.295	0.299
D0	1.40	1.50	1.60	0.055	0.059	0.063
D1	1.40	1.50	1.60	0.055	0.059	0.063
P0	3.90	4.00	4.10	0.154	0.157	0.161
P1	7.90	8.00	8.10	0.311	0.315	0.319
P2	1.90	2.00	2.10	0.075	0.079	0.083
A0	6.85	6.90	7.00	0.270	0.271	0.276
В0	10.45	10.50	10.60	0.411	0.413	0.417
K0	2.68	2.78	2.88	0.105	0.109	0.113
T	0.24		0.27	0.009		0.011
t1	0.10			0.004		
10P0	39.80	40.00	40.20	1.567	1.575	1.583



-30V P-Channel Enhancement Mode MOSFET Attention

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Edition	Date	Change
Rve1.0	2021/1/10	Initial release

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